

2879

03500.015729.

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

SHIN KITAMURA ET AL.

Application No.: 09/940,643

Filed: August 29, 2001

For: ELECTRON-EMITTING DEVICE,
 ELECTRON SOURCE,
 IMAGE-FORMING APPARATUS, AND
 METHOD FOR PRODUCING
 ELECTRON-EMITTING DEVICE AND
 ELECTRON-EMITTING APPARATUS

Examiner: Not Yet Assigned

Group Art Unit: 2879

November 17, 2003

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

TECHNOLOGY CENTER 2800

NOV 19 2003

RECEIVED

THIRD SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449. Copies of the listed documents are also enclosed, as is a copy of a June 27, 2003, Korean Communication citing non-English documents KR 1999-019614 and JP 10-199398, issued in a counterpart Korean application. A Japanese translation of the Korean communication and a Japanese translation of

document KR 1999-019614 also are enclosed. No English translations or English abstracts of these non-English documents are presently available.

For a concise explanation of relevance for various other non-English documents listed on the enclosed Form PTO-1449, the Examiner is directed to the corresponding English-language abstracts, English translations, and/or English counterparts, where available, as indicated in association with the relevant non-English documents on the Form PTO-1449.

For the concise statement of relevance of non-English document CN 1181607A, the Examiner also is respectfully referred to English-language counterparts EP 0 836 217 A1 and WO 99/58748.

The Examiner's attention is also directed to the following U.S. Application:

<u>APPLICATION NO.</u>	<u>FILING DATE</u>	<u>GROUP ART UNIT</u>
09/666,605 /	09/20/00	2811

A copy of the cited application is enclosed.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our New York office by telephone at (212) 218-2100. All correspondence should continue to be directed to our address given below.

Respectfully submitted,



Attorney for Applicants

Registration No. 42,476


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NY MAIN_ #367750v1

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 03500.015729.		APPLICATION NO. 09/940,643	
Date Submitted to PTO: [DATE]			APPLICANT Shin Kitamura et al.			
			FILING DATE August 29, 2001			GROUP 2879
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	5,982,091	11/99	Konishi	313	495	
	6,400,091 B1	06/02	Deguchi et al.	315	169.1	
	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98
	5,872,422	02/99	Xu et al.	313	311	
	6,087,765	07/00	Coll et al.	313	309	
	2002/0009637A1	01/02	Murakami et al.	429	213	02/05/01
	5,847,495	12/98	Yamanobe et al.	313	310	
	5,066,883	11/91	Yoshioka et al.	313	309	
	6,455,021 B1	09/02	Saito	423	447.3	07/20/99
	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00
	4,728,851	03/88	Lambe	313	309	
	5,773,921	06/30/98	Keesman et al.	313	309	
	5,973,444	10/26/99	Xu et al.	313	309	
	5,935,639	8/10/99	Sullivan et al.	427	78	
	4,956,578	9/11/90	Shimizu et al.	315	3	
	5,185,554	2/9/93	Nomura et al.	313	495	
	6,448,709	9/02	Chuang et al.	313	497	
	6,204,597	03/01	Xie et al.	313	310	
EXAMINER			DATE CONSIDERED			

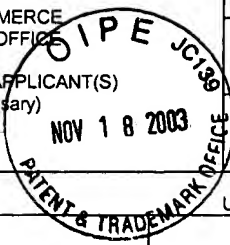
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Sheet 1 of 10

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	5,577,943	11/96	Vickers et al.	445	24	
	2002/136896	09/26/00	Takikawa et al.	428	408	
	5,192,240	03/09/93	Komatsu	445	24	
	5,214,346	05/25/93	Komatsu	313	309	
	5,382,867	01/17/95	Maruo et al.	313	309	
	5,612,587	03/18/97	Itoh et al.	313	309	
	6,313,572 B1	11/06/01	Yamada	313	310	
	6,135,839	10/24/00	Iwase et al.	445	24	
	2001/0006232	07/05/01	Choi et al.	257	40	
	4,816,289	03/89	Komatsu et al	423	447.3	
	5,443,859	08/95	Nagata	427	422	
	5,618,875	04/97	Baker et al.	524	495	
	5,690,997	11/97	Grow	427	249.1	
	6,129,602	10/00	Yamanobe	445	24	
	6,228,904	05/01	Yadav et al.	523	210	
	6,333,016	12/01	Resasco et al.	423	447.3	
	6,413,487	07/02	Resasco et al.	423	447.3	
	6,445,006	09/02	Brandes et al.	257	76	
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Sheet 2 of 10

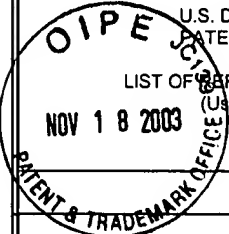
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	6,290,564	9/01	Talin et al.	445	50	
	5,458,784	10/95	Baker et al.	210	674	
	6,331,690 B1	12/01	Yudasaka et al.	219	121.6	
	5,965,267	10/99	Nolan et al.	428	408	
	6,309,612 B1	05/02	Kotaki et al.	347	85	
	5,872,541	02/99	Yoshioka et al.	345	121.1	
	5,543,684	08/96	Kumar et al.	313	495	
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	4,900,483	2/90	Witzke et al.	313	309	
	5,500,200	3/96	Mandeville et al.	423	447.3	
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	2003/0048056 A1	03/03	Kitamura et al.	313	311	
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	11-194134	07/99	Japan	G01N	37/08	Abst., European Equivalent 0 913 508 A2 & Counterpart U.S. Patent 6,313,572
	11-139815	05/99	Japan	C01B	31/02	Abst.
	0 535 953 B1	01/96	EPO	H01J	1/30	English
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	WO 01/93292 A1	12/01	PCT	H01J	1/304	English
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	3-20941	01/29/91	JAPAN	H01J	31/12	Abst. & Counterpart U.S. Patent 5,185,554
	5-211029	08/20/93	JAPAN	H01J	1/30	No
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	1 113 478 A1	07/01	EPO	H01J	3/02	English
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	05-159696	06/25/93	Japan	H01J	1/30	Counterpart U.S. Patents 5,382,867 & EP 0 535 953
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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

APPLICANT

Shin Kitamura et al.

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

FILING DATE

August 29, 2001

GROUP

2879

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	2001-288625 A	10/01	Japan	D01F	9/127	Abst., Counterpart U.S. Patent 2002/00009637 & EP 1 122 344
	0 433 507 A1	6/91	EPO	D01F	9/127	English
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)			
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		Sashiro Uemura et al., "Carbon Nanotube FED with Graphite-Nano-Fiber Emitters," <i>ISSN 1083-1312</i> , pp. 398-401.			
		Q. H. Wang et al., "A Nanotube-Based Field-Emission Flat Panel Display," <i>Applied Physics Letters</i> , Vol. 72, No. 22, June 1998, pp. 2912-2913			
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